Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10519100	LERICHE ET AL.
Examiner	Art Unit
YI CHEN	2142

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SEARCHED				
Class	Subclass	Date	Examiner	
709	203	9/2/2008	Yi Chen	

SEARCH NOTES		
Search Notes	Date	Examiner
Full text search of US patents, US-pubs, and EPO, JPO, Derwent and IBM-TDB databases	9/12/2008	Yi Chen
Assignee Search	9/13/2008	Yi Chen
Inventor name search	9/12/2008	Yi Chen

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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